INTERNATIONAL TEST CONFERENCE 1994

# Proceedings
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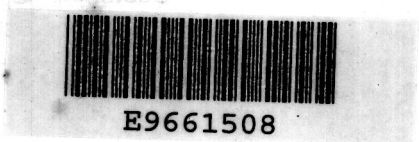

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**ITC Office**
205 Tennyson Avenue, Suite C
Altoona, PA 16602 USA
Tel: (814) 941-4666

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# Welcoming Message

Welcome to the 25th International Test Conference, the premier technical conference on electronic testing. By joining us at ITC 94, you are participating in a week of activities aimed at your professional development and the development of the test profession.

Hundreds of ITC volunteers, staff, and presenters have created **ITC Test Week**, a week of activities including formal papers, panel discussions, exhibits, tutorials, test standard working meetings, and other professional society meetings. In response to last year's popularity, ITC again offers the Exhibitors Forum the day before the technical program. This forum provides a convenient snapshot of today's available test technology and helps to organize your visit to the Exhibit Floor.

ITC paper selection is highly competitive and these Proceedings include many of the finest test technology papers in the world. This year's conference celebrates twenty-five years of the annual test conference and looks forward with optimism to the next twenty-five. The plenary session provides a short look at prior conferences but the primary focus is to the future, in accordance with this year's theme: *Test: The Next Twenty-Five Years*. Several panel discussions also provide insight into industry and technology trends.

This year's conference introduces a new format that incorporates both leading-edge and mainstream subjects. One such leading-edge topic, *Test Synthesis*, features a new tutorial, panel discussion, and special day-long seminar. *Multi-chip module (MCM) Testing* is another emerging technology and the conference features two sessions, a panel discussion, and a tutorial on this important topic.

*Boundary scan* and *$I_{DDQ}$-related testing* continue to be popular as test technology evolves, but other topical areas are gaining in interest. *Mixed-Signal Testing* continues its explosive growth in both variety and complexity of applications. *Systems Testing* is continuing its revolutionary change towards more structure, coordination of DFT tools at all system levels, and standardization.

ITC's traditional test topics are also well represented at ITC. There are sessions devoted to *ATPG, test equipment hardware, software testing, DFT, applied BIST, board testing, test economics, memory testing, test engineering,* and *test quality and reliability.* These sessions could provide that crucial spark of inspiration that leads to innovative solutions in your own work.

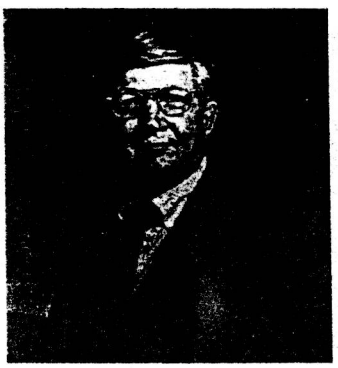
**ITC Test Week** offers an abundant variety of outstanding exhibits, technical papers, panel discussions, and tutorials. For example: A new digital test engineering tutorial has been developed to meet the needs of test professionals in the 90s. The popular ISO 9000 tutorial is again offered for ITC attendees at no extra cost. Many technical meetings held during Test Week provide numerous opportunities to learn, contribute, and form professional networks.

You will get the most from ITC by participating in as much as you can. Our social events in the historic Washington D.C. area offer the opportunity to add to your professional network and renew old acquaintances. Finally, please take time to fill out our survey so we can improve ITC to better meet your needs.

*Gerald Gordon*
*General Chair*

*William Bruce*
*Program Chair*

Gerald Gordon



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**Program Chair**
Bill Bruce
Motorola Inc.
6501 Wm. Cannon Dr. W.
MS 0E321
Austin, TX 78735
512 891-2279

**Program Vice Chair**
John Masciola
GenRad Inc.
300 Baker Avenue, M/S 6
Concord, MA 01742
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**Asian Subcommittee Chair**
Takashi Tokuno
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Saitama 349-11
JAPAN
+81-480-72-6300

**Asian Subcommittee Vice Chair**
Mitsuaki Ishikawa
Toshiba Corp.
580-1 Horikawa-Cho, Saiwai-Ku
Kawasaki, 210
JAPAN
+81-44-548-2741

**European Subcommittee Chair**
Paolo Prinetto
Politecnico di Torino
Corso Duca degli Abruzzi 24
Dept. Auto. Info
I-10129 Torino TO,
ITALY
+39-11-564-7007

**European Subcommittee Vice Chair**
Christian Landrault
LIRMM
161 rue Ada, UMR CNRS C09928
34392 Montpellier Cedex 5
FRANCE
+33 67 41 85 24

**Program Planning Subcommittee Chair**
Kenneth Parker
Hewlett-Packard
814 14th St.,S.W.,P.O.Box 301,
MS AU100
Loveland, CO 80539
303 679-2500

**Program Planning Subcommittee Vice Chair**
Ben Bennetts
Synopsys Inc
700 East Middlefield Road
Mountain View, CA 94043-4033
415 694 4244

**D&T Techniques ATC**
Dilip K. Bhavsar
Digital Equipment Corp.
77 Reed Road HL02-3/D11
Hudson, MA 01749
508 568-5668

**Quality & Reliability ATC**
Eugene R. Hnatek
Tandem Computers, Inc.
3908 Woodcreek Lane
San Jose, CA 95117
408-285-2609

**Software Tools & Models ATC**
Robert E. Huston
Credence Systems
3500 W. Warren Avenue
Fremont, CA 94538
510-623-4876

**D&T Applications ATC**
William R. Mann
Rockwell International
4311 Jamboree Boulevard
MS 771-240
Newport Beach, CA 92660
714-622-3132

**Boundary Scan Coordinator**
James Beausang
Synopsys, Inc
700 East Middlefield Road
Mountain View, CA 94043-4033
415-694-1807

**DFT Coordinator**
Dilip K. Bhavsar
Digital Equipment Corp.
77 Reed Road HL02-3/D11
Hudson, MA 01749
508 568-5668

**Synthesis Coordinator**
Kwang-Ting (Tim) Cheng
Univ. of California
Dept. of ECE
Santa Barbara, CA 93106
805-893-7204

**ATPG Coordinator**
Scott Davidson
AT&T Bell Labs
P.O. Box 900
Princeton, NJ 08542-0900
609-639-2289

**Tester Software Coordinator**
Arthur E. Downey
Credence
3500 W. Warren Avenue
Fremont, CA 94538
510-623-4824

**Memory Test Coordinator**
Tohru Furuyama
Toshiba R&D Cntr.
1 Komukai-Toshiba-cho, Saiwai-ku
Kawasaki-shi, 210
JAPAN
+81-44-549-2209

**Microprocessor Test Coordinator**
Grady Giles
Motorola Inc.
6501 Wm. Cannon Dr. W.
MS OE37
Austin, TX 78735
512-891-2271

**Board Test Coordinator**
David Greene
AT&T Global Info. Solutions
3325 Platt Springs Road, MS 751
West Columbia, SC 29170
803-939-6161